

**Search Notes**

Application/Control No.

10/750,465

Examiner

Mike Fatahiyar

Applicant(s)/Patent under  
Reexamination

CHEN, NIEN-TSU

Art Unit

2629

**SEARCHED**

Class	Subclass	Date	Examiner
345	156-184	4/28/2007	MF
341	35	4/28/2007	MF
200	11R-11TW	4/29/2007	MF
463	36-39	4/29/2007	MF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search	4/28/2007	MF